Editorial

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Biographical notes: Dong-Wook Oh is an Associate Professor in the Department of Mechanical Engineering at Chosun University, South Korea. He received his PhD in Mechanical Engineering from Seoul National University. Prior to joining Chosun University, he worked as a Post-Doctoral Researcher at the Department of Material Science and Engineering, University of Illinois at Urbana-Champaign, and a Senior Researcher at the Department of Advanced Thermal Systems, Korea Institute of Machinery and Materials. His current research is focused on thermal characterization and application of thermal systems based on microdevices.

Yeon Suk Choi received a PhD in Mechanical Engineering from Florida State University and currently is the Principal Researcher in the Division of Scientific Instrument at the Korea Basic Science Institute, South Korea. His research interests include the development of physical property measuring equipment, measurement and analysis of thermal property, heat and mass transfer at low temperature and superconducting magnet applications.

The *21st Korean Thermophysical Properties (KSTP) Conference* was held online on 15–16 April 2021. The conference was organised by Dr. Taejin Park, Korean Atomic Energy Research Institute. The conference was held online due to COVID-19 and the resulting social distancing policy of the Korean government. Regardless of the physical distance between the attendees, numerous exciting papers on advances in thermophysical property measurements in micro/nano-scale were presented and in-depth discussions took place in the cyber-space.

This special issue is a collection of 11 papers that are revised and expanded from the original conference presentation. All papers are carefully selected and peer-reviewed by domestic and international reviewers. This issue covers aspects of micro/nano-scale thermophysics in measurement and instrumentation.

We would like to thank all the authors and reviewers for their professionalism and contribution to this special issue. Special gratitude should also be given to Dr. Lionel Vayssieres, Editor-in-Chief of the *International Journal of Nanotechnology*, for providing this wonderful opportunity.